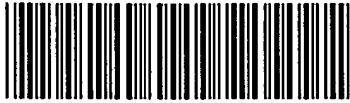


Search Notes

Application/Control No.

10/649,729

Examiner

Blake E. Betz

Applicant(s)/Patent under
Reexamination

SHIMIZU, KOICHI

Art Unit

2672

SEARCHED

Class	Subclass	Date	Examiner
345	441	3/2/2005	BB
	428	3/7/2005	BB

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
simplif\$4 same detail\$3 and model with creat\$3 and plane and point	3/2/2005	BB
simplif\$3 with display with object same user	3/7/2005	BB